

N-Ch 100V Fast Switching MOSFETs

Features:

- ★ Super Low Gate Charge
- ★ Excellent CdV/dt effect decline
- ★ Green Device Available
- ★ Advanced high cell density Trench technology

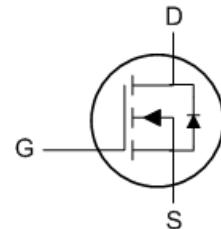


Description:

The KEP0016 is the high cell density trenched N-ch MOSFETs, which provide excellent RDSON and gate charge for most of the synchronous buck converter applications.

The KEP0016 meet the RoHS and Green Product requirement, 100% EAS guaranteed with full function reliability approved.

TO220 Pin Configuration



Product Summary

BVDSS	RDS(on)	ID
100V	47mΩ	27A

Absolute Maximum Ratings

Symbol	Parameter	Rating	Units
V _{DS}	Drain-Source Voltage	100	V
V _{GS}	Gate-Source Voltage	±20	V
I _D @T _c =25°C	Continuous Drain Current, V _{GS} @ 10V ¹	27	A
I _D @T _c =100°C	Continuous Drain Current, V _{GS} @ 10V ¹	17	A
I _D @T _A =25°C	Continuous Drain Current, V _{GS} @ 10V ¹	4.2	A
I _D @T _A =70°C	Continuous Drain Current, V _{GS} @ 10V ¹	3.3	A
I _{DM}	Pulsed Drain Current ²	54	A
EAS	Single Pulse Avalanche Energy ³	36.5	mJ
I _{AS}	Avalanche Current	27	A
P _D @T _c =25°C	Total Power Dissipation ⁴	87	W
P _D @T _A =25°C	Total Power Dissipation ⁴	2	W
T _{STG}	Storage Temperature Range	-55 to 150	°C
T _J	Operating Junction Temperature Range	-55 to 150	°C

Thermal Data

Symbol	Parameter	Typ.	Max.	Unit
R _{θJA}	Thermal Resistance Junction-ambient ¹	---	62	°C/W
R _{θJC}	Thermal Resistance Junction-Case ¹	---	1.44	°C/W

Electrical Characteristics ($T_J=25\text{ }^{\circ}\text{C}$, unless otherwise noted)

Symbol	Parameter	Conditions	Min.	Typ.	Max.	Unit
BV_{DSS}	Drain-Source Breakdown Voltage	$V_{GS}=0\text{V}$, $I_D=250\mu\text{A}$	100	---	---	V
$\Delta BV_{DSS}/\Delta T_J$	$BVDSS$ Temperature Coefficient	Reference to $25\text{ }^{\circ}\text{C}$, $I_D=1\text{mA}$	---	0.098	---	V/C
$R_{DS(\text{ON})}$	Static Drain-Source On-Resistance ²	$V_{GS}=10\text{V}$, $I_D=20\text{A}$	---	---	47	$\text{m}\Omega$
		$V_{GS}=4.5\text{V}$, $I_D=15\text{A}$	---	---	50	
$V_{GS(\text{th})}$	Gate Threshold Voltage	$V_{GS}=V_{DS}$, $I_D=250\mu\text{A}$	1.0	---	2.5	V
$\Delta V_{GS(\text{th})}$	$V_{GS(\text{th})}$ Temperature Coefficient		---	-5.52	---	mV/C
I_{DSS}	Drain-Source Leakage Current	$V_{DS}=80\text{V}$, $V_{GS}=0\text{V}$, $T_J=25\text{ }^{\circ}\text{C}$	---	---	10	uA
		$V_{DS}=80\text{V}$, $V_{GS}=0\text{V}$, $T_J=55\text{ }^{\circ}\text{C}$	---	---	100	
I_{GSS}	Gate-Source Leakage Current	$V_{GS}=\pm 20\text{V}$, $V_{DS}=0\text{V}$	---	---	± 100	nA
g_{fs}	Forward Transconductance	$V_{DS}=5\text{V}$, $I_D=20\text{A}$	---	28.7	---	S
R_g	Gate Resistance	$V_{DS}=0\text{V}$, $V_{GS}=0\text{V}$, $f=1\text{MHz}$	---	1.6	---	Ω
Q_g	Total Gate Charge (10V)	$V_{DS}=80\text{V}$, $V_{GS}=10\text{V}$, $I_D=20\text{A}$	---	60	---	nC
Q_{gs}	Gate-Source Charge		---	9.7	---	
Q_{gd}	Gate-Drain Charge		---	11.8	---	
$T_{d(on)}$	Turn-On Delay Time	$V_{DD}=50\text{V}$, $V_{GS}=10\text{V}$, $R_G=3.3\Omega$	---	10.4	---	ns
T_r	Rise Time		---	46	---	
$T_{d(off)}$	Turn-Off Delay Time		---	54	---	
T_f	Fall Time		---	10	---	
C_{iss}	Input Capacitance	$V_{DS}=15\text{V}$, $V_{GS}=0\text{V}$, $f=1\text{MHz}$	---	3848	---	pF
C_{oss}	Output Capacitance		---	137	---	
C_{rss}	Reverse Transfer Capacitance		---	82	---	

Diode Characteristics

Symbol	Parameter	Conditions	Min.	Typ.	Max.	Unit
I_s	Continuous Source Current ^{1,5}	$V_G=V_D=0\text{V}$, Force Current	---	---	27	A
I_{SM}	Pulsed Source Current ^{2,5}		---	---	54	A
V_{SD}	Diode Forward Voltage ²	$V_{GS}=0\text{V}$, $I_s=1\text{A}$, $T_J=25\text{ }^{\circ}\text{C}$	---	---	1.2	V
t_{rr}	Reverse Recovery Time	$ I =20\text{A}$, $dI/dt=100\text{A}/\mu\text{s}$, $T_J=25\text{ }^{\circ}\text{C}$	---	30	---	nS
Q_{rr}	Reverse Recovery Charge		---	37	---	nC

Note :

- 1.The data tested by surface mounted on a 1 inch²FR-4 board with 2OZ copper.
- 2.The data tested by pulsed , pulse width $\leq 300\mu\text{s}$, duty cycle $\leq 2\%$
- 3.The EAS data shows Max. rating . The test condition is $V_{DD}=25\text{V}$, $V_{GS}=10\text{V}$, $L=0.1\text{mH}$, $I_{AS}=27\text{A}$
- 4.The power dissipation is limited by $150\text{ }^{\circ}\text{C}$ junction temperature
- 5.The data is theoretically the same as I_D and I_{DM} , in real applications , should be limited by total power dissipation.

Typical Characteristics

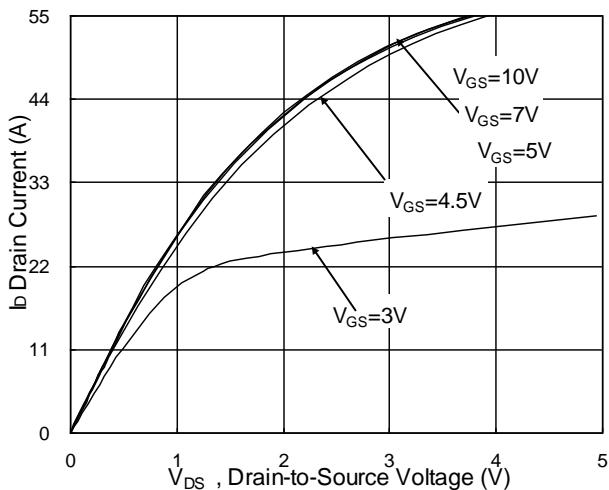


Fig.1 Typical Output Characteristics

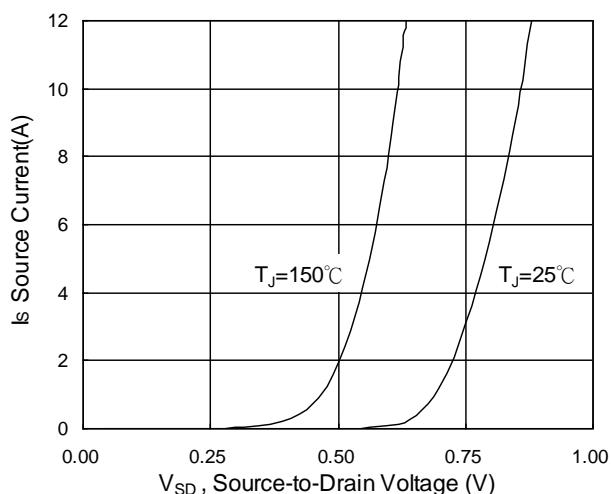


Fig.3 Forward Characteristics Of Reverse

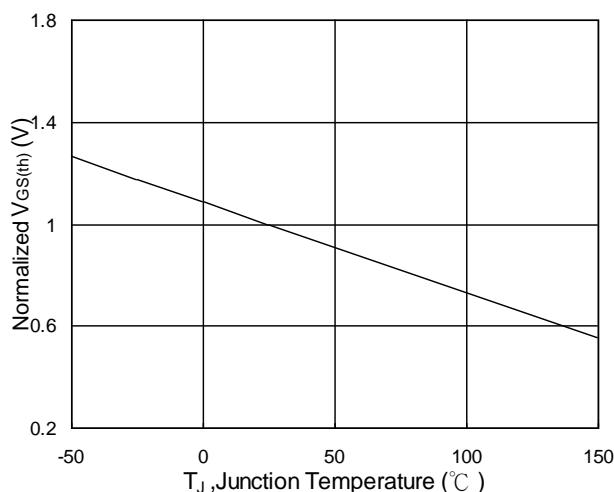


Fig.5 Normalized V_{Gs(th)} vs. T_J

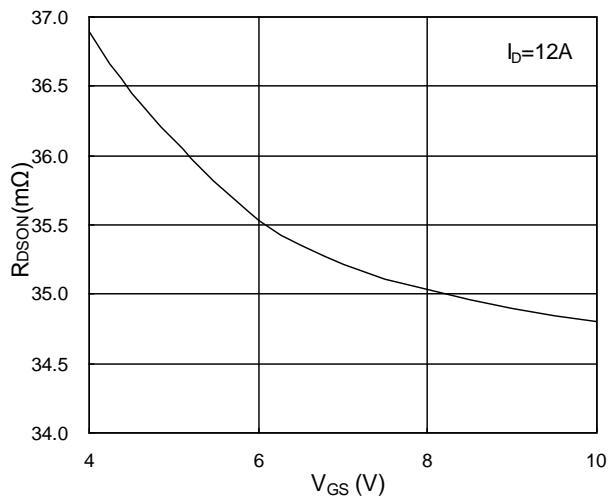


Fig.2 On-Resistance vs. Gate-Source

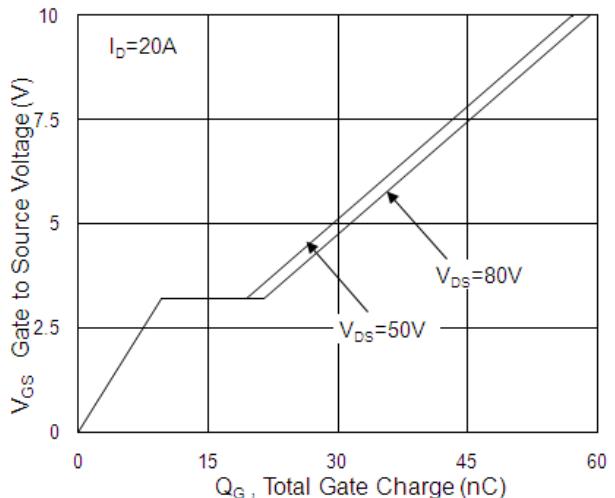


Fig.4 Gate-Charge Characteristics

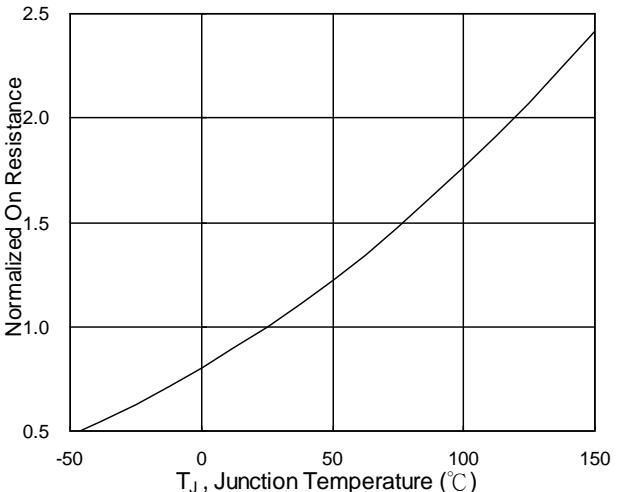
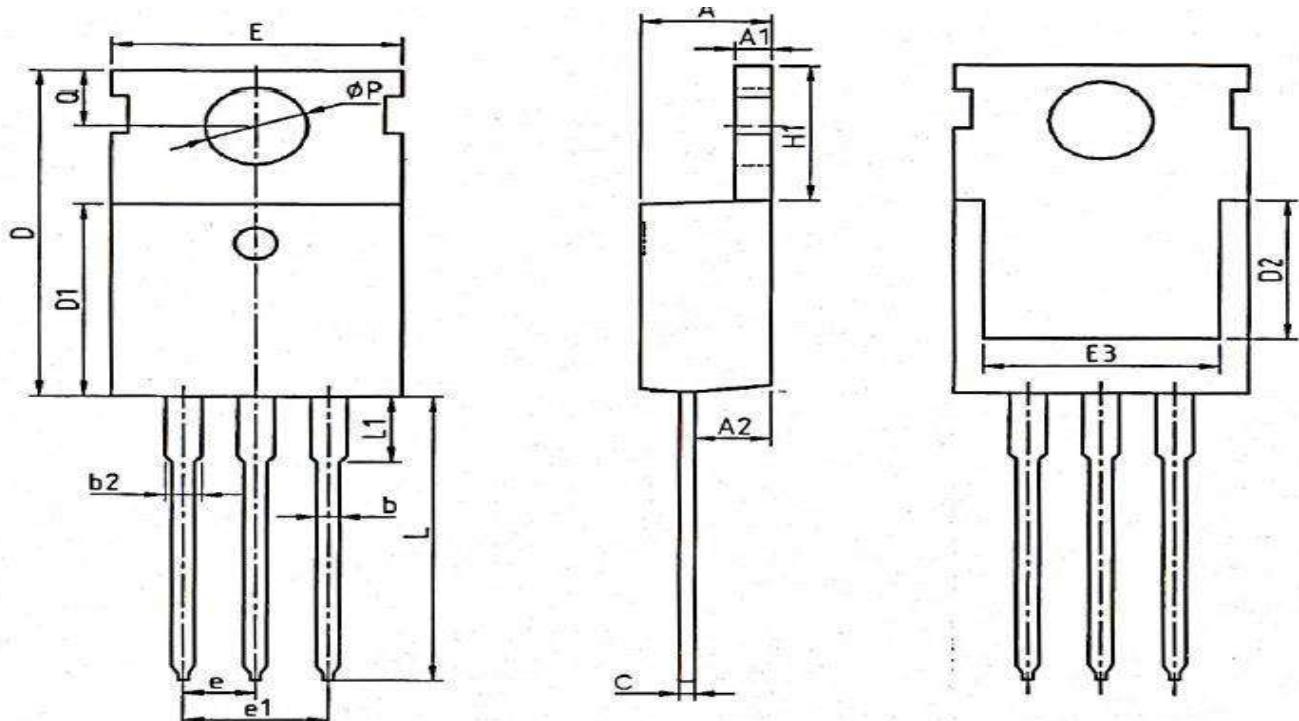


Fig.6 Normalized R_{DSON} vs. T_J

TO-220_3L Package Outline



SYMBOLS	MILLIMETERS		INCHES	
	MIN	MAX	MIN	MAX
A	3.556	4.826	0.14	0.19
A1	0.508	1.4	0.02	0.055
A2	2.032	2.921	0.08	0.115
b	0.381	1.016	0.015	0.04
b2	1.143	1.778	0.045	0.07
c	0.356	0.61	0.014	0.024
D	14.224	16.51	0.56	0.65
D1	8.382	9.017	0.33	0.355
D2	5.5	-	0.216	-
E	9.652	10.668	0.38	0.42
E3	6.858	-	0.27	-
e	2.540 BSC		0.100 BSC	
e1	5.080 BSC		0.200 BSC	
H1	5.842	6.858	0.23	0.27
L	12.7	14.732	0.5	0.58
L1	-	4.06	-	0.16
Q	2.54	3.048	0.1	0.12